

BSC029N025S G-VB Datasheet N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Typ.)	
30	0.0018 at V _{GS} = 10 V	0	82 nC	
	0.0025 at V _{GS} = 4.5 V		OZ IIC	

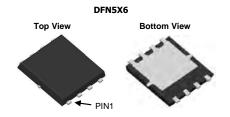
FEATURES

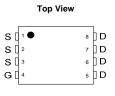
- Trench Power MOSFET
- 100 % R_g and UIS Tested

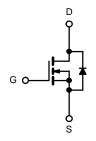
COMPLIANT

APPLICATIONS

- OR-ing
- Server







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS} 30	30	V	
Gate-Source Voltage		V _{GS}	± 20		
Continuous Drain Current (T _J = 175 °C)	T _C = 25 °C		a, e	A	
	T _C = 70 °C		90 ^e		
	T _A = 25 °C	I _D	33 ^{b, c}		
	T _A = 70 °C		29.8 ^{b, c}		
Pulsed Drain Current		I _{DM}	300		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	36		
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	64.8	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	90 ^{a, e}		
Continuous Source-Diain Diode Current	T _A = 25 °C	'S	3.13 ^{b, c}	A	
	T _C = 25 °C		250 ^a	w	
Mayimum Dawar Dissination	T _C = 70 °C	P _D	175		
Maximum Power Dissipation	T _A = 25 °C	rD	3.75 ^{b, c}		
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6		

Notes:

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		m\//°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	i _D = 250 μA		- 7.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.5		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α	
Drain-Source On-State Resistance ^a		$V_{GS} = 10 \text{ V}, I_D = 32 \text{ A}$		0.0018		Ω	
	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 29 \text{ A}$		0.0025			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 32 A		160		S	
Dynamic ^b	_		I.	"		L	
Input Capacitance	C _{iss}						
Output Capacitance	C _{oss}	V_{DS} = 12.5 V, V_{GS} = 0 V, f = 1 MHz			1725	pF	
Reverse Transfer Capacitance	C _{rss}				970		
Tatal Cata Channa	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 32 \text{ A}$				nC	
Total Gate Charge							
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 29 \text{ A}$			34		
Gate-Drain Charge	Q_{gd}				29		
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.555 Ω		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 27$ A, $V_{GEN}=10$ V, $R_g=1$ Ω		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 0.625 \Omega$		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 24$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		55	83		
Fall Time	t _f			12	18		
Drain-Source Body Diode Characteristic	s		L				
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			100	A	
Pulse Diode Forward Current ^a	I _{SM}				200		
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 20 A di/dt 100 A/vo T 25 °C		70.2	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27		ns	
Reverse Recovery Rise Time	t _b			25			

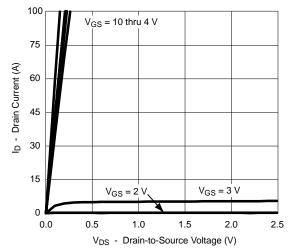
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

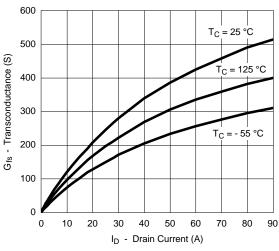
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



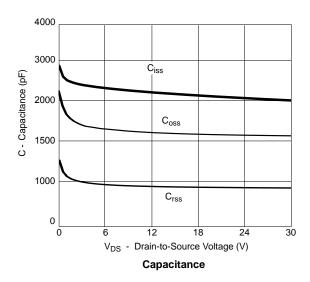
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

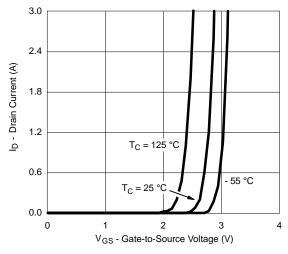


Output Characteristics

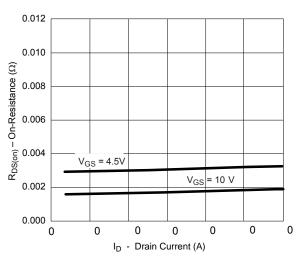


Transconductance

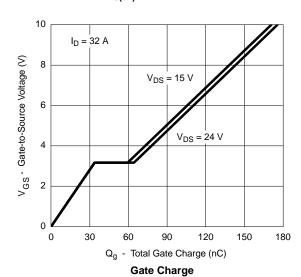




Transfer Characteristics

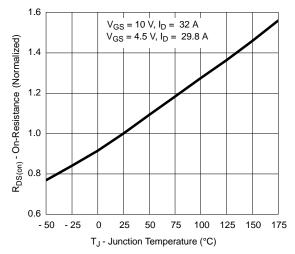


R_{DS(on)} vs. Drain Current

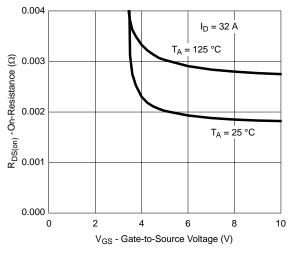




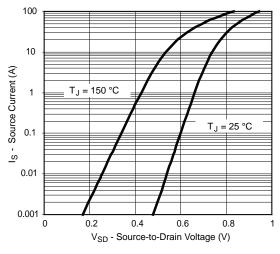
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



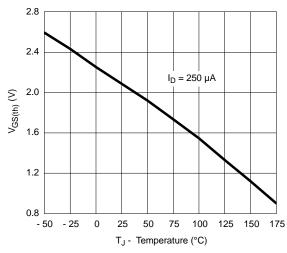
On-Resistance vs. Junction Temperature



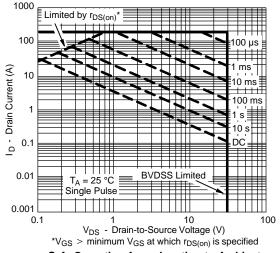
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



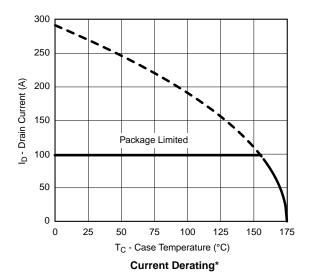
Threshold Voltage

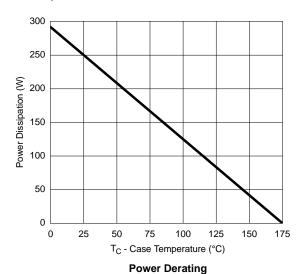


Safe Operating Area, Junction-to-Ambient

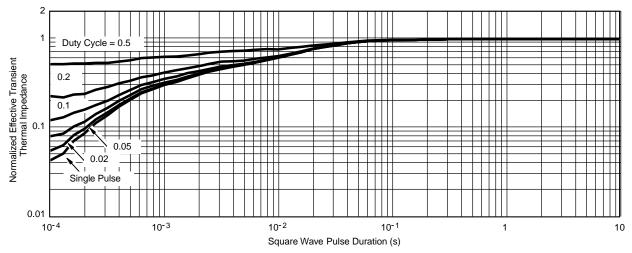


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

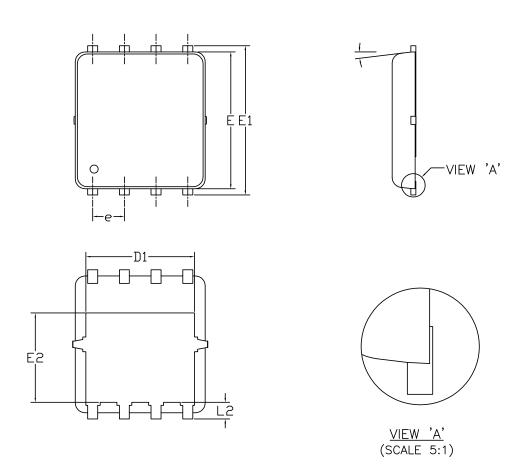




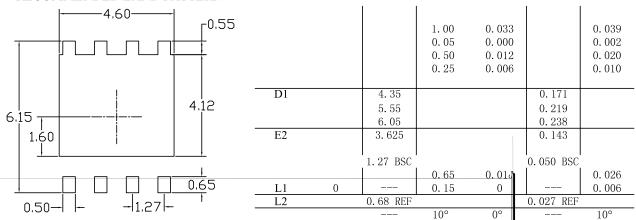
^{*} The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



RECOMMENDED LAND PATTERN



NOTE

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
 MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm



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